# IEEE Standard for eXtensible <br> Event Stream (XES) for Achieving Interoperability in Event Logs and Event Streams 

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Standar ee
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(Revision of IEEE Std 1849-2016)

## Participants

At the time this draft standard was completed, the XES Working Group had the following membership:
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Eric Verbeek, Secretary

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The following members of the individual Standards Association balloting group voted on this standard. Balloters may have voted for approval, disapproval, or abstention.

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When the IEEE SA Standards Board approved this standard on 5 June 2023, it had the following membership:

David J. Law, Chair
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